

Automotive-grade N-channel 100 V, 2.3 mΩ typ., 180 A STripFET™ F7 Power MOSFET in a TO-220 package

Datasheet - production data

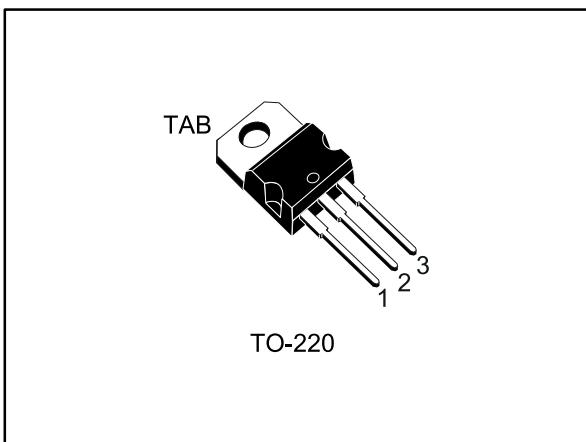
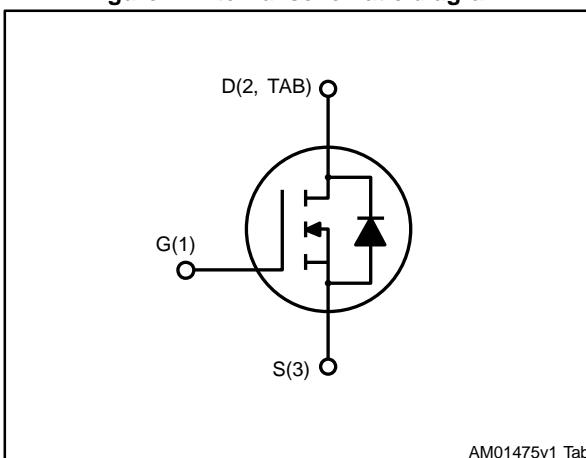


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)max}	I _D
STP315N10F7	100 V	2.7 mΩ	180 A

Features

- Designed for automotive applications and AEC-Q101 qualified
- Among the lowest R_{DS(on)} on the market
- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

- Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

Order code	Marking	Package	Packaging
STP315N10F7	315N10F7	TO-220	Tube

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	100	V
V_{GS}	Gate-source voltage	± 20	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	180	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	120	A
$I_{DM}^{(2)}$	Drain current (pulsed)	720	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	315	W
$E_{AS}^{(3)}$	Single pulse avalanche energy ($T_J = 25^\circ\text{C}$, $L=0.55\text{ mH}$, $I_{AS}=65\text{ A}$)	1	J
T_J	Operating junction temperature range	$-55 \text{ to } 175$	$^\circ\text{C}$
T_{stg}	Storage temperature range		

Notes:

(1) Current limited by package.

(2) Pulse width limited by safe operating area.

(3) Starting $T_J=25^\circ\text{C}$, $I_D=60\text{ A}$, $V_{DD}=50\text{ V}$.**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	0.48	$^\circ\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient	62.5	$^\circ\text{C/W}$

2 Electrical characteristics

($T_C = 25^\circ\text{C}$ unless otherwise specified)

Table 4: On /off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V}, T_C = 125^\circ\text{C}$ (1)			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = 20 \text{ V}$			100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.5	3.5	4.5	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		2.3	2.7	$\text{m}\Omega$

Notes:

(1)Defined by design, not subject to production test.

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	-	12800	-	pF
C_{oss}	Output capacitance		-	3500	-	pF
C_{rss}	Reverse transfer capacitance		-	170	-	pF
Q_g	Total gate charge	$V_{DD} = 50 \text{ V}, I_D = 180 \text{ A}, V_{GS} = 10 \text{ V}$ (see Figure 14: "Test circuit for gate charge behavior")	-	180	-	nC
Q_{gs}	Gate-source charge		-	78	-	nC
Q_{gd}	Gate-drain charge		-	34	-	nC

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 50 \text{ V}, I_D = 90 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 13: "Test circuit for resistive load switching times" and Figure 18: "Switching time waveform")	-	62	-	ns
t_r	Rise time		-	108	-	ns
$t_{d(off)}$	Turn-off delay time		-	148	-	ns
t_f	Fall time		-	40	-	ns

Table 7: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		180	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		720	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}, I_{SD} = 60 \text{ A}$	-		1.5	V
t_{rr}	Reverse recovery time	$I_{SD} = 180 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 80 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$ (see <i>Figure 15: "Test circuit for inductive load switching and diode recovery times"</i>)	-	85		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 80 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$ (see <i>Figure 15: "Test circuit for inductive load switching and diode recovery times"</i>)	-	200		nC
I_{RRM}	Reverse recovery current		-	4.7		A

Notes:

(1)Pulse width limited by safe operating area.

(2)Pulse duration = 300μs, duty cycle 1.5%

2.2 Electrical characteristics (curves)

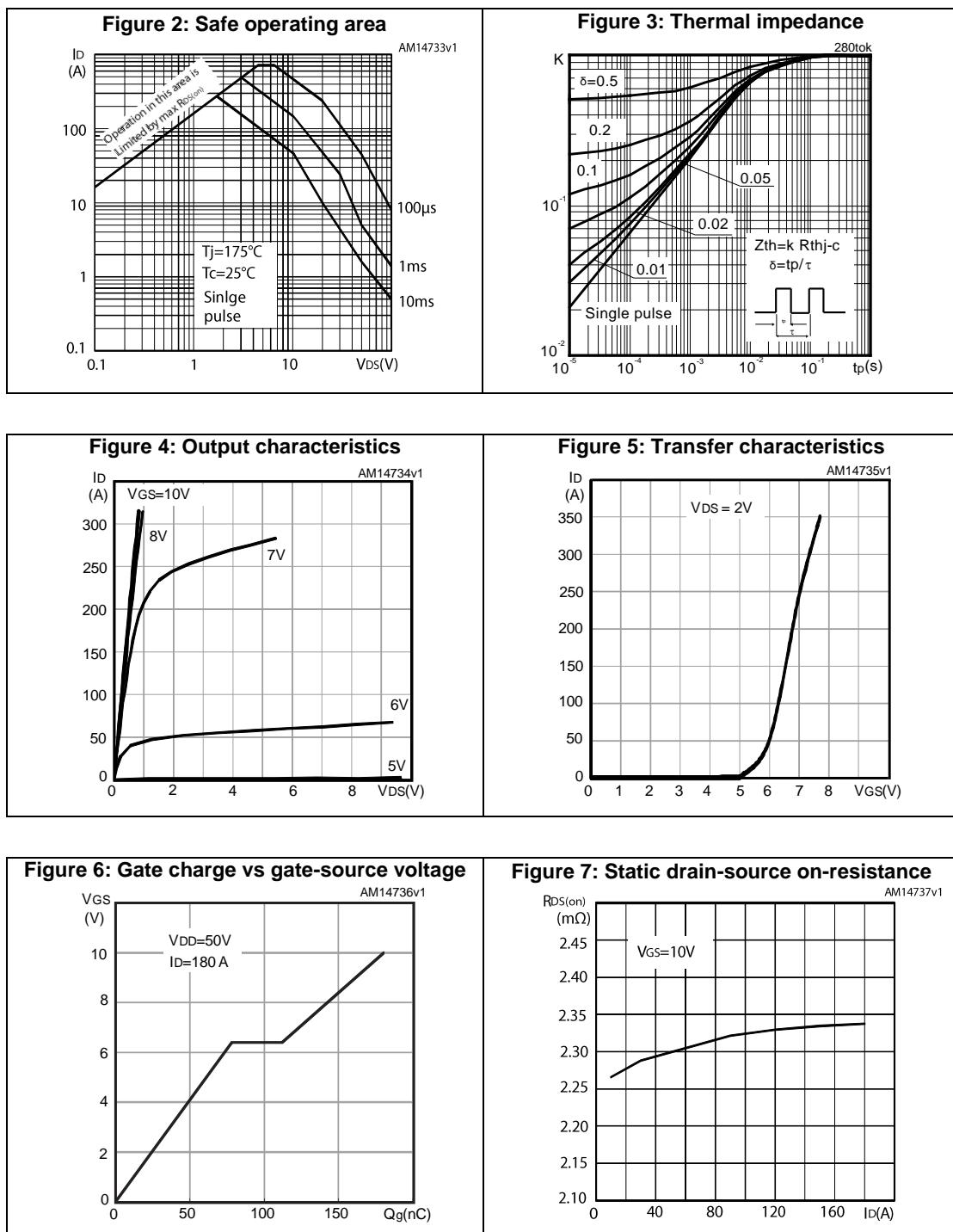
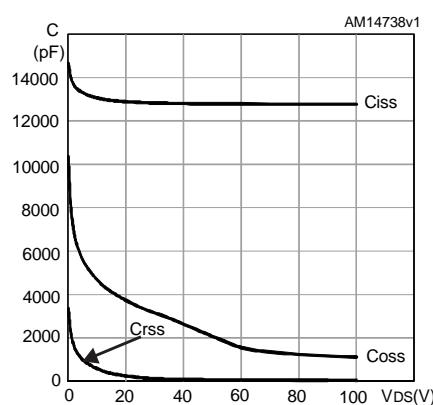
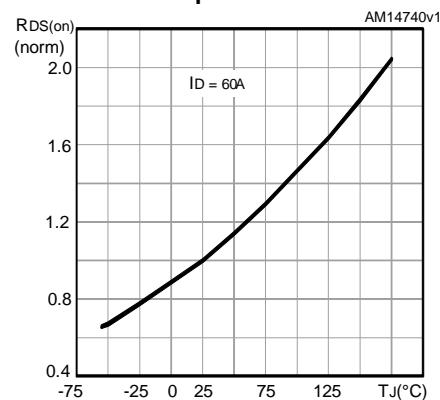
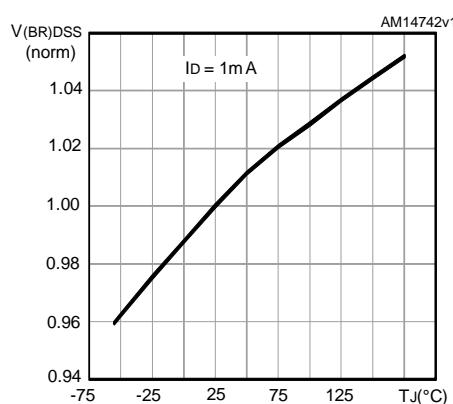
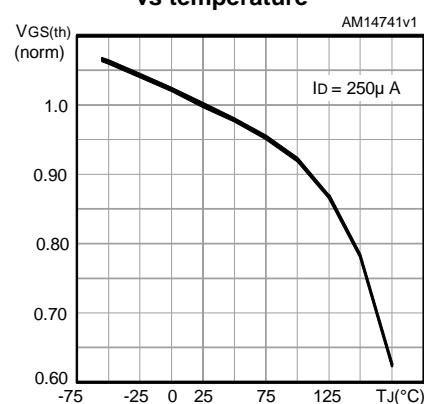
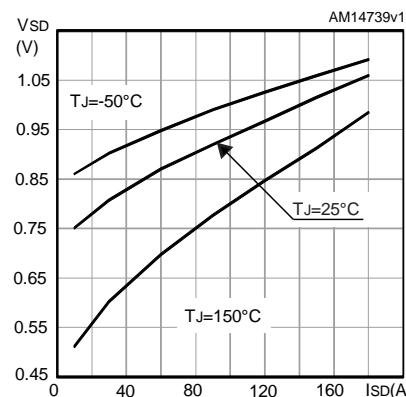


Figure 8: Capacitance variations**Figure 9: Normalized on-resistance vs temperature****Figure 10: Normalized V_{(BR)DSS} vs temperature****Figure 11: Normalized gate threshold voltage vs temperature****Figure 12: Source-drain diode forward characteristics**

3 Test circuits

Figure 13: Test circuit for resistive load switching times

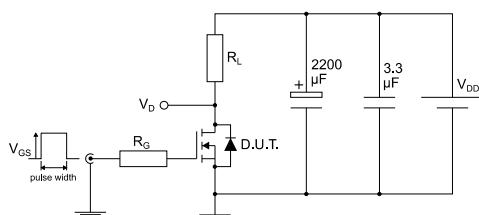


Figure 14: Test circuit for gate charge behavior

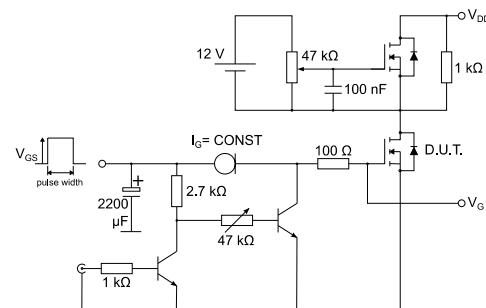


Figure 15: Test circuit for inductive load switching and diode recovery times

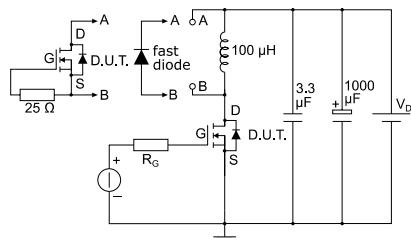


Figure 16: Unclamped inductive load test circuit

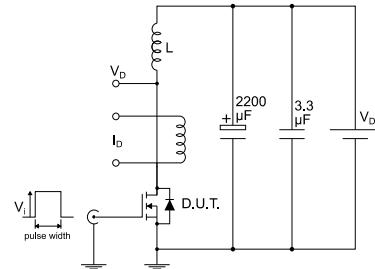


Figure 17: Unclamped inductive waveform

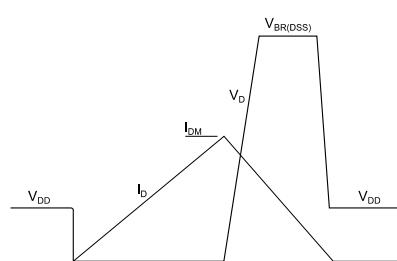
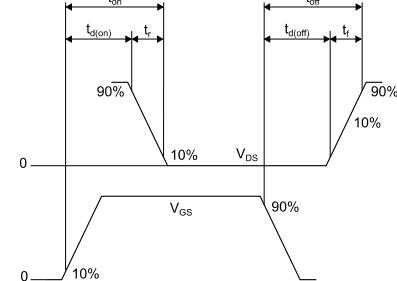


Figure 18: Switching time waveform



4 Package information data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
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4.1 TO-220 type A package information

Figure 19: TO-220 type A package outline

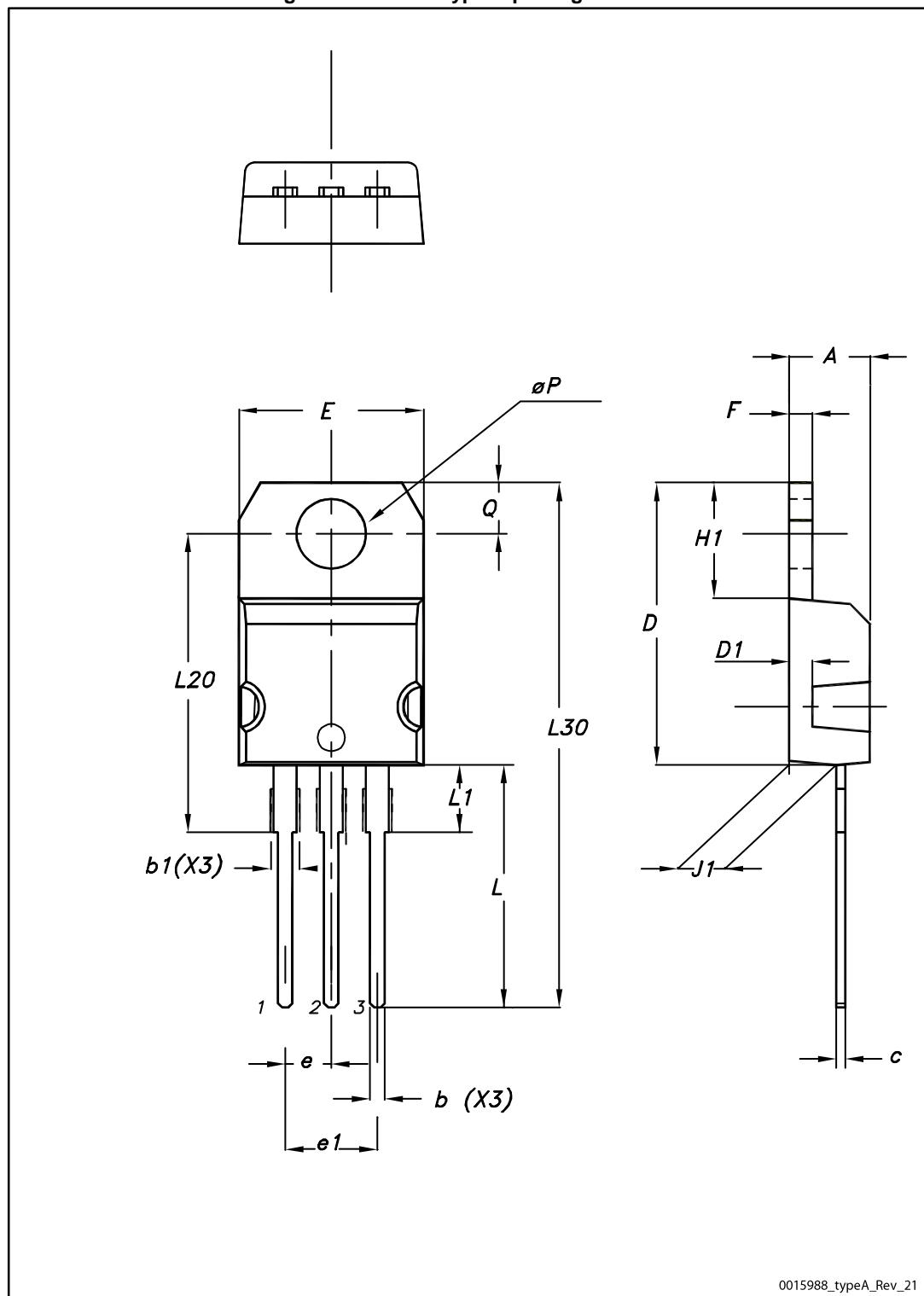


Table 8: TO-220 type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
07-Oct-2013	1	First release.
27-May-2014	2	– Modified: title and <i>Features</i> in cover page – Minor text changes
12-Sep-2014	3	– Modified: title, features and description in cover page.
29-Aug-2016	4	Modified: <i>Table 2: "Absolute maximum ratings"</i> and <i>Table 4: "On /off states"</i> Updated: <i>Section 7.1: "TO-220 type A package information"</i> Minor text changes

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